



Studies on charging-up of single Gas Electron Multiplier

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Motivation

- In general, charging-up is a common phenomenon seen in gaseous ionization detectors with exposed dielectric components.
- Gas Electron Multiplier (GEM) has a large amount of insulating material exposed to the active gas volume.
- Charging-up process includes two sub-processes (polarization of dielectric and accumulation of charges on the dielectric)
- We have tried to identify the effects of these two processes on the effective gain stability, separately, as well as in combination.

Types of charging-up

Polarization charging-up

- Very high field across dielectric (up to 104 kV/cm)
- Polarization of dielectric
- Modification of local field leading to gain variation

Radiation charging-up

- High density of charges around the dielectric
- Charges gets trapped within the dielectric
- Modification of local field leading to gain variation

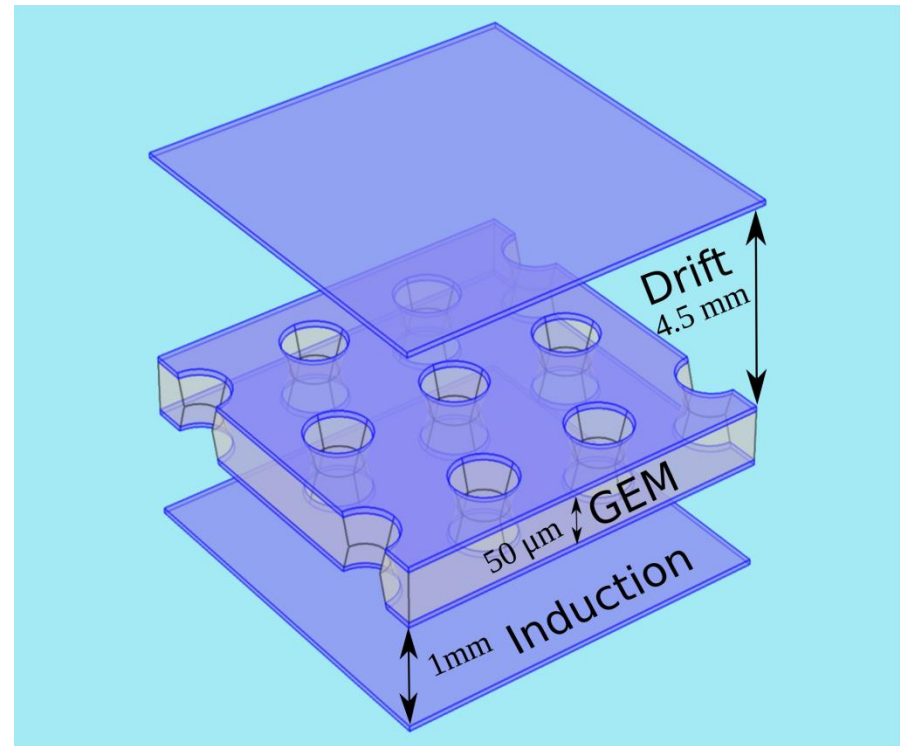
Outlook

- Experimental setup
- Gain measurement
- Polarization charging-up
- Radiation charging-up
- Radiation charging-down
- Conclusions

Experimental setup

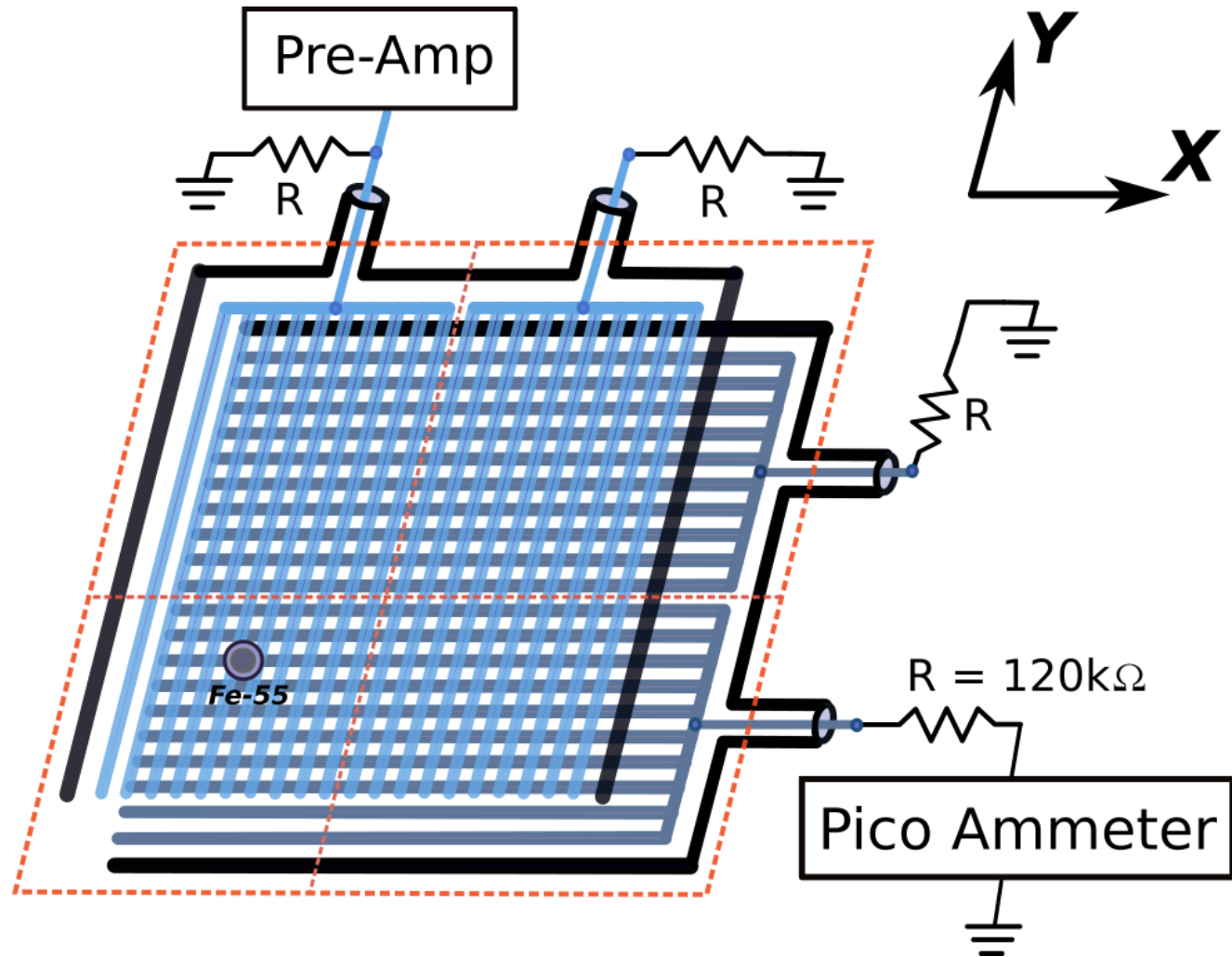
GEM foil

- 50 μm Kapton sheet sandwiched between two copper layers of 5 μm
- Biconical holes of 50 μm and 70 μm inner and outer diameter
- Etched out by chemical lithographic technique in a hexagonal pattern.

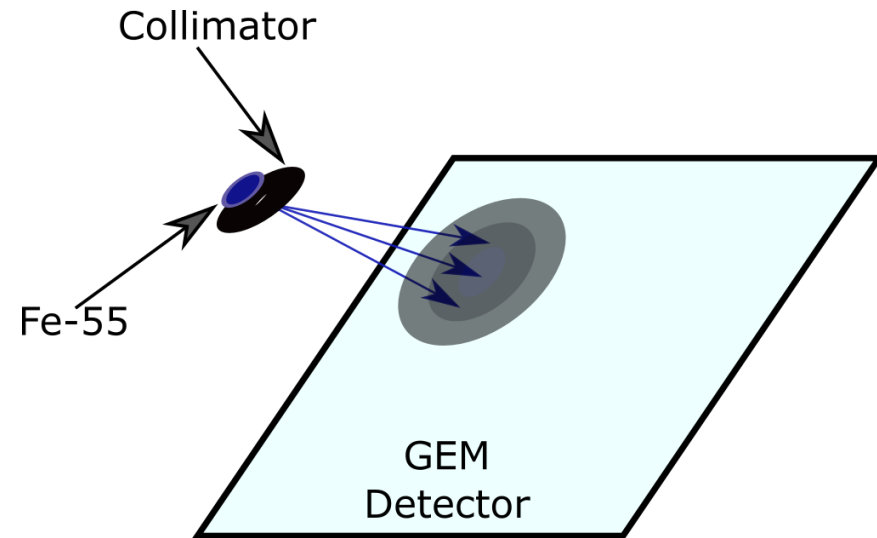


Schematic diagram of single GEM detector.

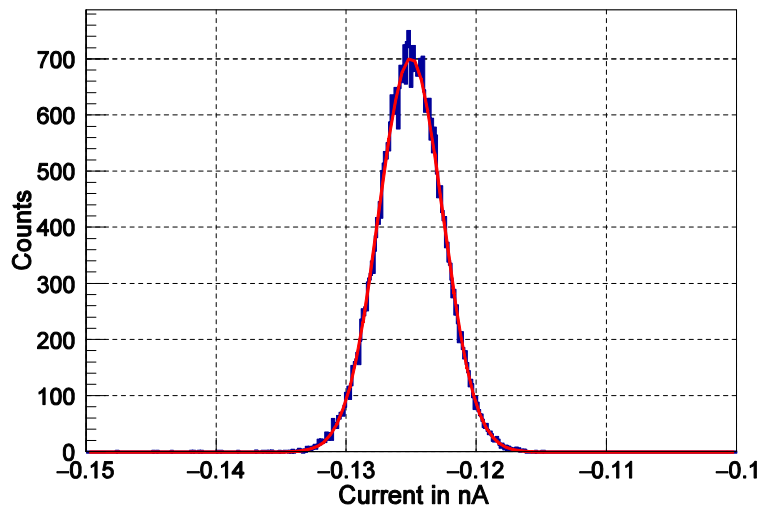
Readout anode configuration



- Aperture of collimator 1-10 mm
- Radiation rate 0.12-25.5 kHz (of 5.9 keV X-ray)



Schematic diagram of irradiation



- Pico-ammeter CEAN AH401D
- Centroid -125.0 pA
- Sigma 2.47 pA

Gaussian fit for repeated current measurement with 4.0 kHz source to get the accuracy in the current.

Gain measurement

$$G_{eff} = \frac{I \cdot \Delta t}{\sum_i N_i \cdot p_i \cdot e}$$

Where,

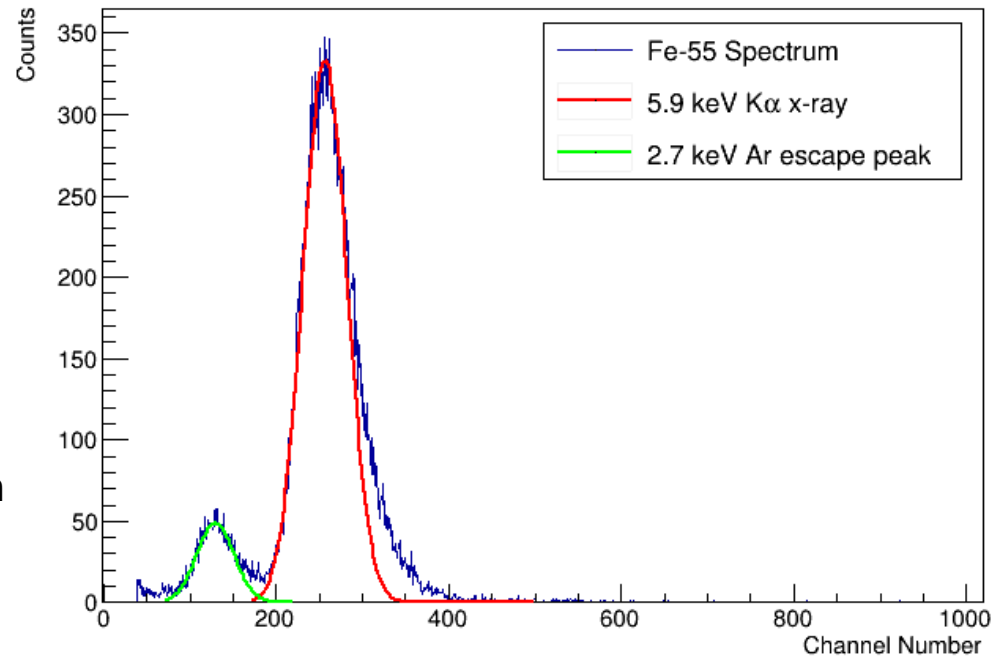
I is average current from the pico-ammeter,

Δt is the time interval for energy spectra,

e is charge of an electron,

N_i is the number of counts in i^{th} channel,

p_i is its corresponding no. of primaries.





No. of primaries for 5.9 and 2.7 keV are generated by Garfield++ using HEED for Ar-CO₂ (74-26%) gas mixture and used to calibrate p_i values.

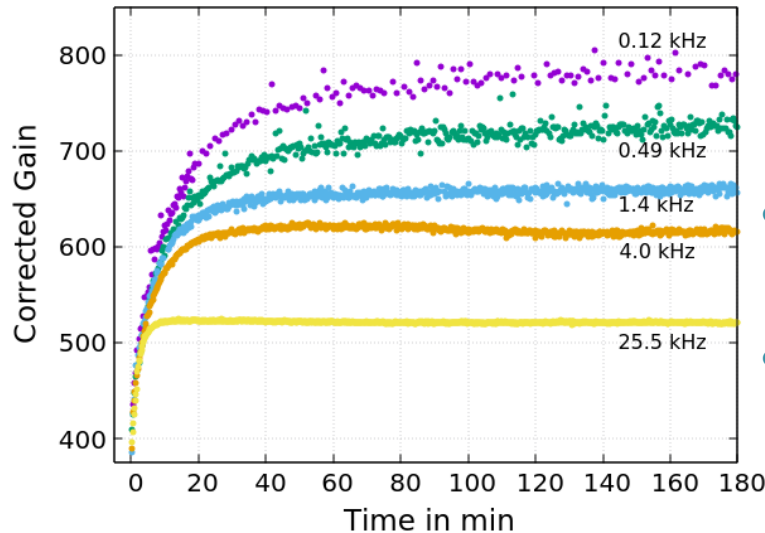
Gain measurement

$$G_{eff} = \frac{I \cdot \Delta t}{\sum_i N_i \cdot p_i \cdot e}$$

← optimized to be large enough to get the energy spectrum for the Gaussian fitting and small enough to capture the changes caused by charging-up with time.

- Channel number  Energy values
(using two peak calibration from Gaussian fit)
- Energy values  p_i values
(using two point calibration since no. of primaries are known for 5.9 and 2.7 keV, numerically)

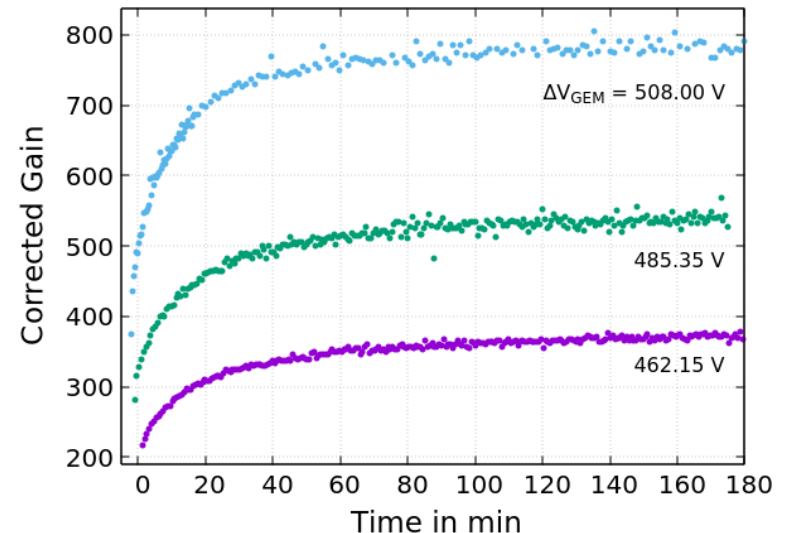
Polarization charging-up



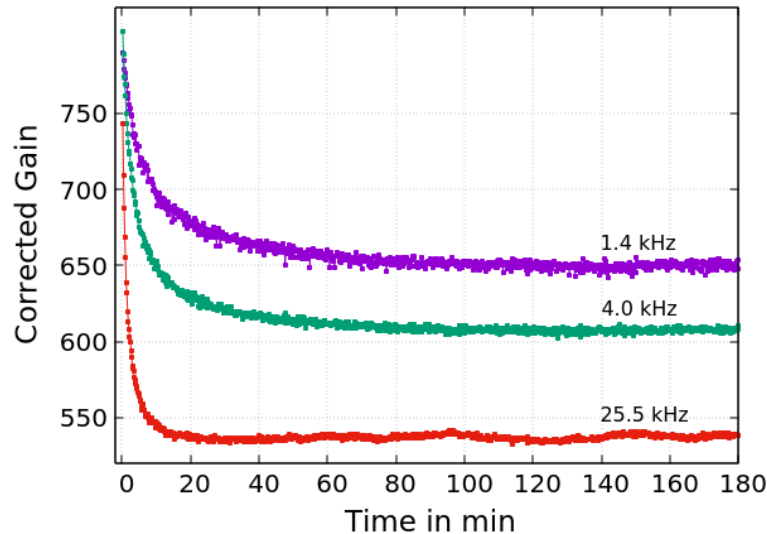
The detector has been kept without bias and radiation for few days before performing the experiment.

- Fixed voltage ΔV_{GEM} and V_{Drift} applied at $t=0$ with $\Delta V_{\text{GEM}} = 508.35 \text{ V}$
- Repeated by varying radiation rate

- Fixed voltage ΔV_{GEM} and V_{Drift} applied at $t=0$
- Radiation rate 120 Hz
- Repeated by varying ΔV_{GEM}



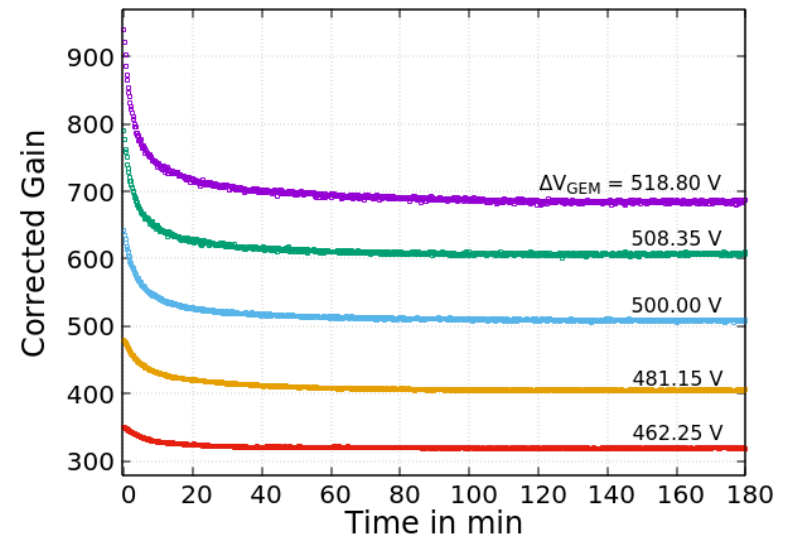
Radiation charging-up



The detector has been kept at its respective potential values for days before irradiation.

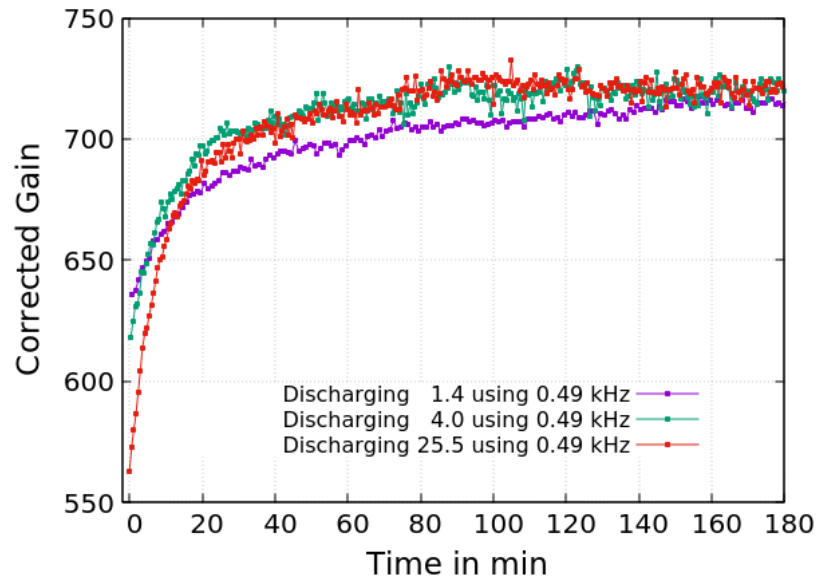
- Fixed ΔV_{GEM} , and V_{Drift} with $\Delta V_{\text{GEM}} = 508.35 \text{ V}$
- Repeated by varying radiation rate

- Radiation rate 4.0 kHz
- Fixed V_{Ind} and ΔV_{GEM}
- Repeated by varying ΔV_{GEM}



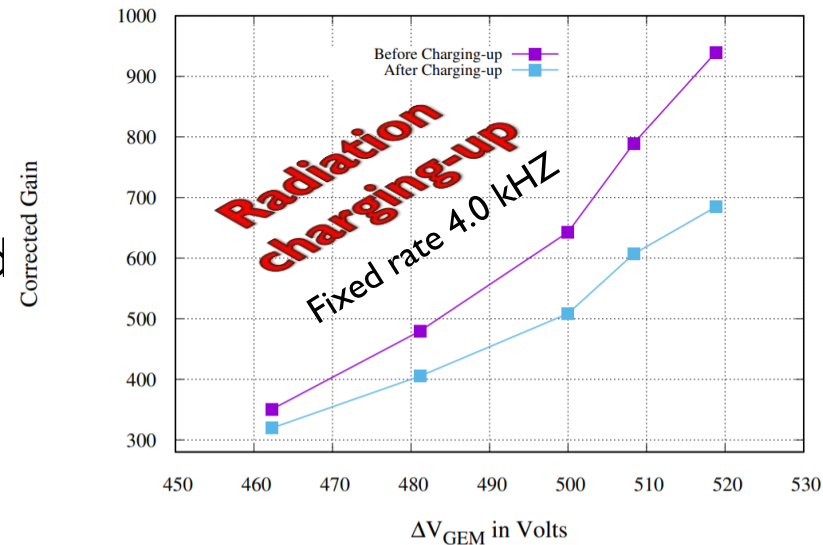
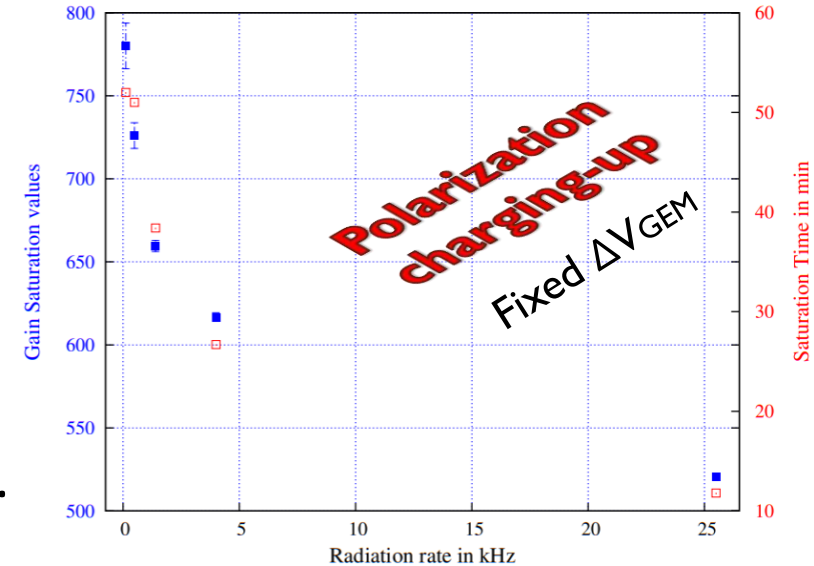
Radiation charging-down

- After charging-up with high rate
- High rate source is replaced by test probe
- Test probe radiation rate = 0.49 kHz
- Fixed ΔV_{GEM} and V_{drift} with $\Delta V_{\text{GEM}} = 508.35 \text{ V}$



Conclusions

- Both polarization and radiation charging-up have a significant impact on the gain.
- Polarization charging-up increases the gain whereas radiation charging-up reduces it.
- On increasing ΔV_{GEM} the effect of both the charging-up processes increases.
- Increase in radiation rate decreases the gain saturation time in both the process.
- These effects are temporary and the detector comes back to its normal state once the biasing and radiation source are removed.



Collaborators

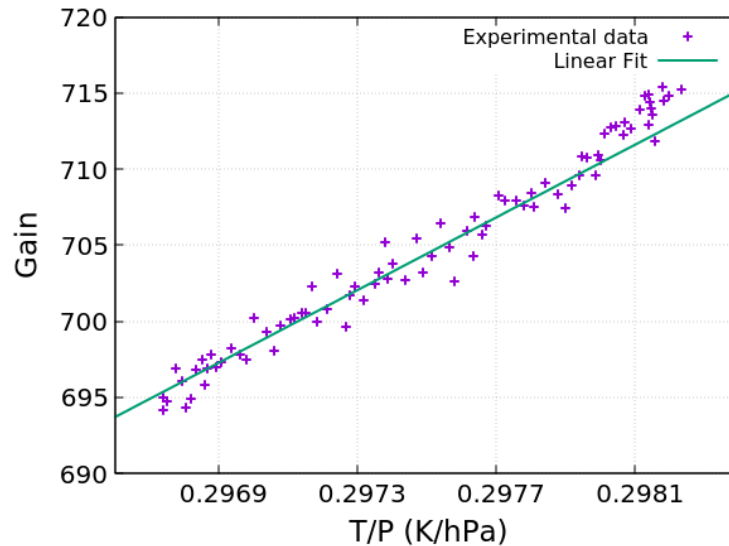
- Prof. Supratik Mukhopadhyay
- Prof. Nayana Majumdar
- Prof. Sandip Sarkar

Acknowledgment

I would like to thank the technical staffs Shaibal Saha, Pradipta K. Das and lab colleagues Anil Kumar, Prasant K. Rout, Promita Roy and Subhendu Das.

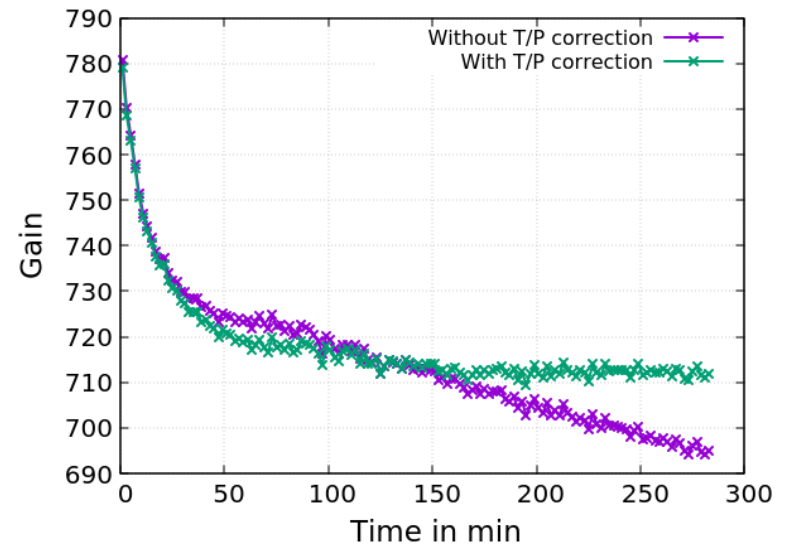
Thank you for listening

Backup I



- Temperature and pressure correction of radiation charging-up data using collimator with a rate of 490 Hz.

- Linear dependence of GEM gain with T/P, with slope 13029.8 hPa/K at 490 Hz.



Backup 2

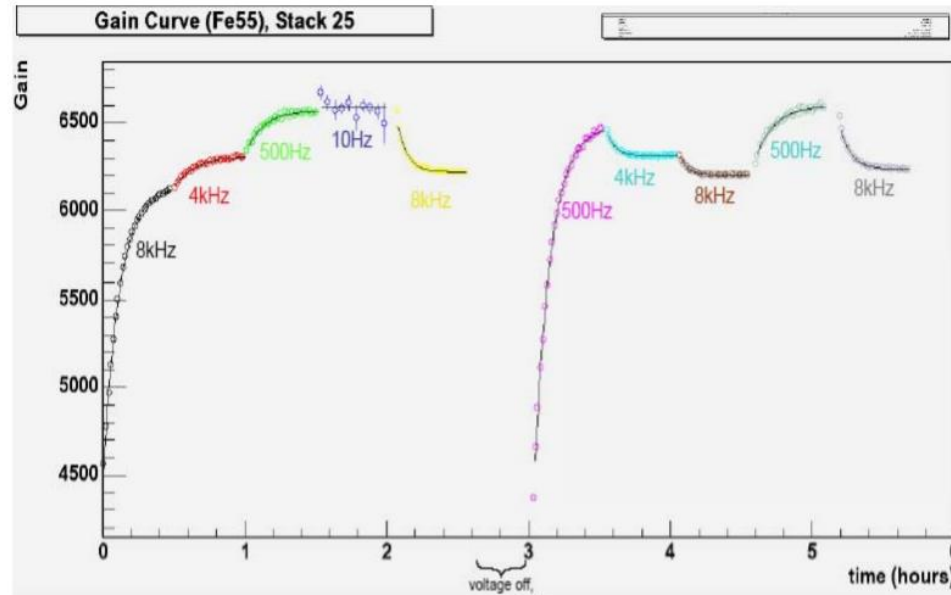
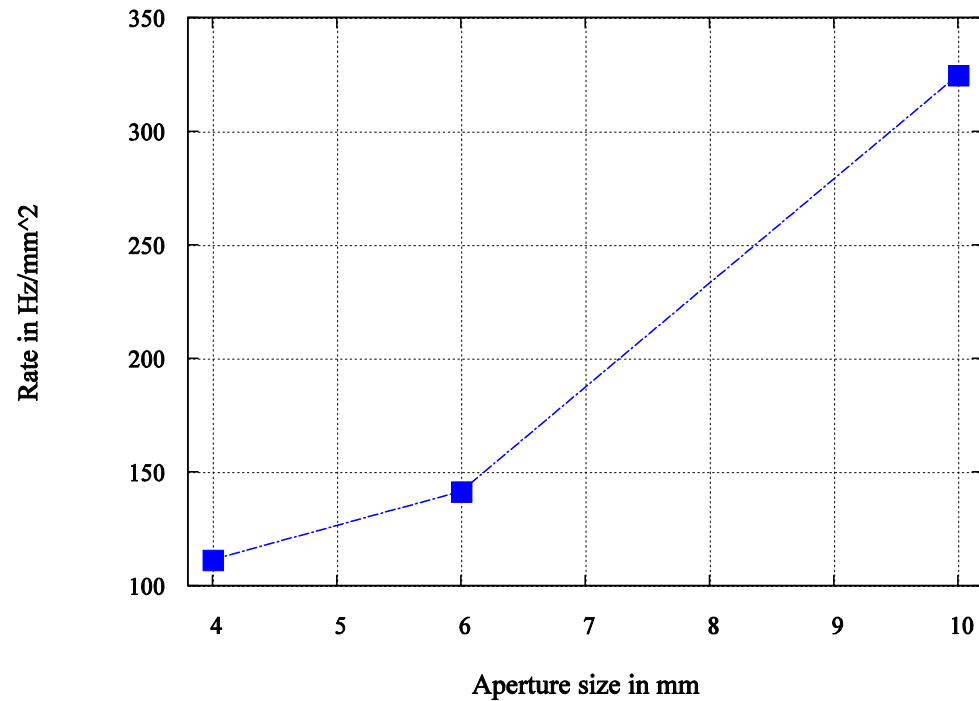


Fig. 5 Gain variation of a triple GEM module consisting of three 23x27 cm² CERN foils used in the PHENIX HBD detector [11]. Rates given are over an area of ~ 5.24 cm². The source intensity was lowered with the high voltage on and then increased. Measurements were then repeated starting at a lower rate.

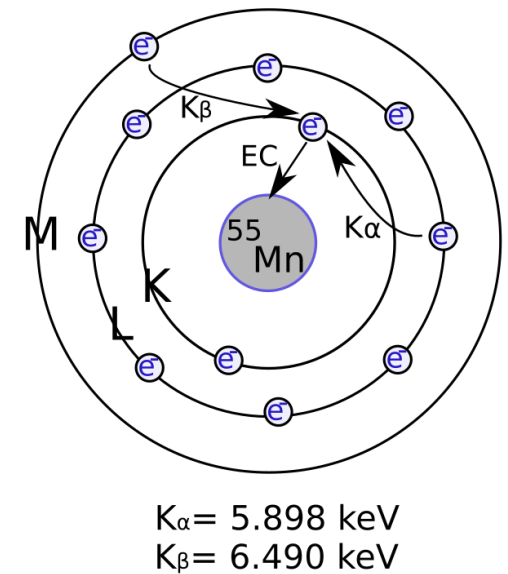
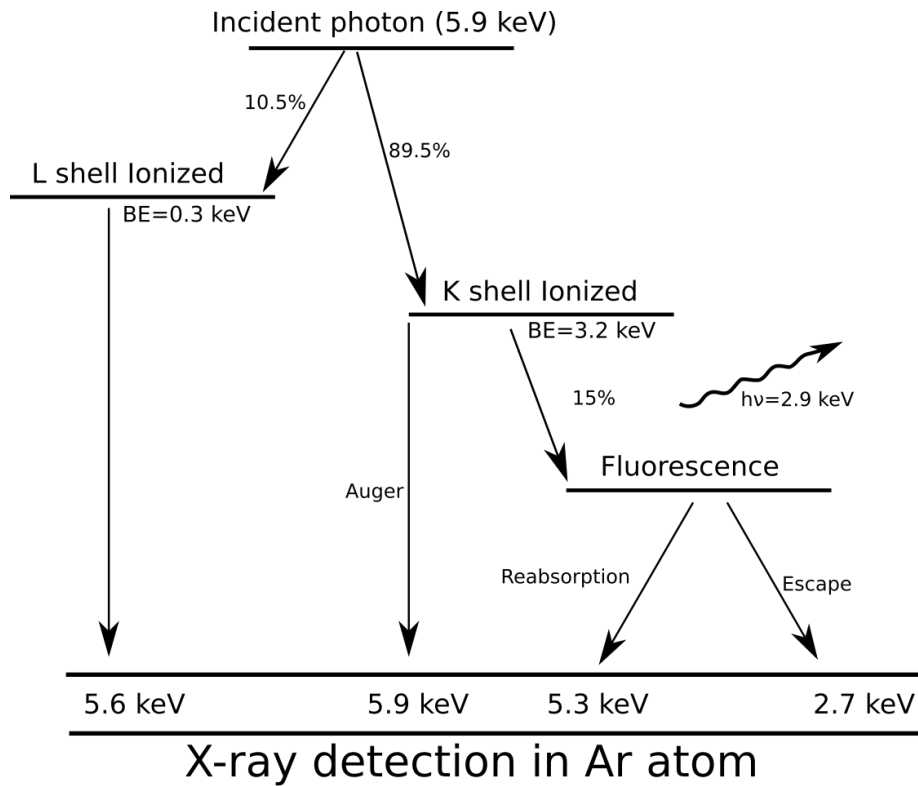
B. Azmoun et al., A Study of Gain Stability and Charging Effects in GEM Foils, IEEE Nuclear Science Symposium Conference Record (2006) 3847–3851.

Backup 3

- Increase in radiation rate with aperture size



Backup 4



X-ray emission by Fe-55